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# 2019 IEEE/ACM 10th International Symposium on Software and Systems Traceability (SST) **SST 2019**

## Table of Contents

Message from the SST 2019 Workshop Chairs .vii.....  
SST 2019 Organizing Committee .viii.....  
SST 2019 Committees .ix.....

### Keynote

Traceability for a Knowledge-Driven Software Engineering .1.....  
*Smita Ghaisas (TCS Research)*

### Traceability Visualisation

Synchronised Visualisation of Software Process and Product Artefacts: Concept, Design and Prototype  
Implementation .2.....  
*Mujtaba Alshakhouri (Auckland University of Technology), Jim Buchan  
(Auckland University of Technology), and Stephen MacDonell (Auckland  
University of Technology)*

### Traceability Management and Evolution

The Interplay of Design and Runtime Traceability for Non-Functional Requirements .3.....  
*Michael Vierhauser (University of Notre Dame), Jane Cleland-Huang  
(University of Notre Dame), Janet Burge (Colorado College), and Paul  
Grünbacher (Johannes Kepler University)*

Change Impact Analysis for Evolving Configuration Decisions in Product Line Use Case Models .11.....  
*Ines Hajri (University of Luxembourg), Arda Goknil (University of  
Luxembourg), Lionel C. Briand (University of Luxembourg), and Thierry  
Stephany (International Electronics & Engineering S.A.)*

Evolving Software Trace Links between Requirements and Source Code .12.....  
*Mona Rahimi (University of Toronto) and Jane Cleland-Huang (University  
of Notre Dame)*

## Special Track on AI and Traceability

Ideas on Improving Software Artifact Reuse via Traceability and Self-Awareness .13.....  
*Christof Tinnes (Technical University Munich), Andreas Biesdorf (Siemens AG Corporate Technology), Uwe Hohenstein (Siemens AG Corporate Technology), and Florian Matthes (Technische Universität München)*

## Traceability Techniques

University of Kentucky TraceLab Component Similarity Matrix Voting Merge .17.....  
*Jared Payne (University of Kentucky) and Jane Huffman Hayes (University of Kentucky)*

Comparing Traceability through Information Retrieval, Commits, Interaction Logs, and Tags .21.....  
*Marcus Seiler (Heidelberg University), Paul Hübner (Heidelberg University), and Barbara Paech (Heidelberg University)*

Source Code Level Word Embeddings in Aiding Semantic Test-to-Code Traceability .29.....  
*Viktor Csuvik (University of Szeged), András Kicsi (University of Szeged), and László Vidács (University of Szeged)*

A Comparison of Stemming Techniques in Tracing .37.....  
*David Farrar (University of Kentucky) and Jane Huffman Hayes (University of Kentucky)*

**Author Index 45** .....